

Notice of References Cited	Application/Control No. 10/550,577		Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
	Examiner /Susan W. Berman/		Art Unit 1796	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,255,034	07-2001	Shimada et al.	430/281.1
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*	D	US-6,013,415	01-2000	Sakurai et al.	430/281.1
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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